

Spring-loaded test probe

GKS-550 291 050 A 1500

Item GKS-550-0001



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Partner for Future Technology

- Robust, compact design for harsh ICT/FCT applications with limited space
- For optimum contact at the test points (e.g. pads, vias, and pins), various tip styles in different diameters and finishes, as well as various spring forces are available. spring forces.

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General data

| | |
|--------------------------------|---|
| Product group | ICT / FCT (in-circuit test and function test) |
| Sub-product group | Short/robust GKS |
| Series | GKS-550 |
| Grid | 1.27 mm [50 mil] |
| Contacting from | Pad, via |
| Magnetic | Yes |
| Installation type | Plug-in |
| Quick-exchange system | Yes |
| Adjustable installation height | No |
| Non-rotating | No |
| Compatible receptacle(s) | KS-550#KS-550 WL |
| Min. temperature | - 40 °C [- 104 °F] |
| Max. temperature | + 80 °C [+ 176 °F] |
| RoHS-compliant | Yes |

Electrical data

| | |
|---------------------------------------|----------|
| Current load capacity / rated current | 2 A |
| Typical resistance (Ri) | <20 mOhm |

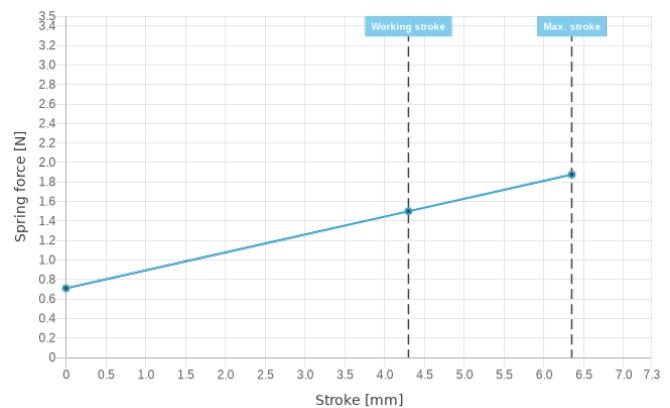
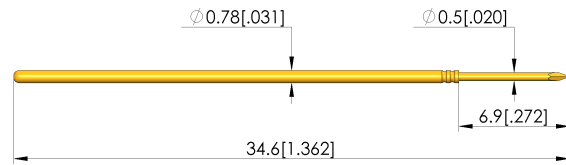
Mechanical data

| | |
|--------------------------------|-------------------|
| Total length | 34.6 mm [1.36 in] |
| Barrel diameter | 0.78 mm [.030 in] |
| Maximum stroke | 6.35 mm [.25 in] |
| Spring pre-load | 0.71 N [2.55 ozf] |
| Collar height | 00 |
| Spring force at working stroke | 1.5 N [5.39 ozf] |
| Recommended working stroke | 4.3 mm [.169 in] |

Tip style data

| | |
|--------------------|--------------------------|
| Tip style | 91 dagger, self-cleaning |
| Tip diameter | 0.5 mm [.019 in] |
| Tip style surface | A gold |
| Tip style material | 2 steel |

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Prices and delivery times on request.
Technical changes reserved. 11/22 EN

Weitere Informationen zum Thema
ICT/FCT Test probes

